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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07844-620001	Application No.	
Inf rmation Disc! sure Statement by Applicant (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant James J. Estrada		
		Filing Date	Group Art Unit 2128	

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Examiner Signature	/Brandon Hsieh/	Date Considered	03/23/2007
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